

Search Notes

Application/Control No.

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Examiner

Anne M. Hines

Applicant(s)/Patent under
Reexamination

HAN, IN-TAEK

Art Unit

2879

SEARCHED

Class	Subclass	Date	Examiner
428	690	10/23/2007	<i>Amt</i>

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
searched East; see East search history.	10/23/2007	<i>Amt</i>